

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.	10/539,247	Conf. No.	9258
In Re Application of:	Gattiker <i>et al.</i>	Art Unit:	2829
Filed:	06/16/2005	Dkt. #:	BUR920020068US1 (IBMF-0010)
		Examiner:	Nguyen, Vinh P.

Title: **INTEGRATED CIRCUIT TESTING METHODS USING WELL BIAS MODIFICATION**

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT UNDER 37 C.F.R. 1.312

Sir:

I. INTRODUCTORY COMMENTS:

This paper is being filed after a Notice of Allowance but before payment of the Issue Fee.

Please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims that begins on page 2 of this paper.

Remarks begin on page 5 of this paper.